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| Notice of References Cited | Application/Control No. 10/042,892 | | Applicant(s)/Patent Under Reexamination LEVERENZ ET AL. | |
| | Examiner B. Chen | | Art Unit 1762 | Page 1 of 1 |

U.S. PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Name | Classification |
|---|---|--|-----------------|----------------------|----------------|
| | A | US-4,830,886 | 05-1989 | Cho et al. | 427/249.19 |
| | B | US-5,750,247 | 05-1998 | Bryant et al. | 428/323 |
| | C | US-5,958,569 | 09-1999 | Leverenz et al. | 428/216 |
| | D | US-3,900,592 | 08-1975 | Kennedy et al. | 427/569 |
| | E | US-4,269,899 | 05-1981 | Fuyama et al. | 428/457 |
| | F | US-6,056,999 | 05-2000 | Narasimhan, Krishnan | 428/699 |
| | G | US- | | | |
| | H | US- | | | |
| | I | US- | | | |
| | J | US- | | | |
| | K | US- | | | |
| | L | US- | | | |
| | M | US- | | | |

FOREIGN PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Country | Name | Classification |
|---|---|--|-----------------|---------|------|----------------|
| | N | | | | | |
| | O | | | | | |
| | P | | | | | |
| | Q | | | | | |
| | R | | | | | |
| | S | | | | | |
| | T | | | | | |

NON-PATENT DOCUMENTS

| * | | Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) |
|---|---|---|
| | U | |
| | V | |
| | W | |
| | X | |

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